

Posters

Mehmet Ince, Sule Ozev and Sarma Vrudhula. [Statistical Library Characterization using Arbitrary Polynomial Chaos Expansions](#)

Mehmet Meric Isgenc, Samuel Pagliarini, Mayler Martins and Larry Pileggi. [Exhaustive DFM Evaluation of Logic Cell Libraries via Virtual Characterization](#)

Shogo Yamaguchi, Hitoshi Imi, Shogo Tokumaru and Kazuyuki Nakamura. [Vth-shiftable SRAM Cell TEGs for Direct Measurement for the Immunity of the Threshold Voltage Variability](#)

Hongge Chen, Duane Boning and Zheng Zhang. [Efficient Spatial Variation Characterization via Matrix Completion](#)

Chiao-Chuan Huang, Hsin Yang, Ting-Yu Shyu and Tay-Jyi Lin. [Timing Margin Prediction for Energy-Efficient and Variation-Resilient Adaptive Voltage Scaling in Microprocessor Designs](#)

Xinfei Guo and Mircea Stan. [Enabling Wearout-Immune BEOL and FEOL with Active Rejuvenation](#)

Michihiro Shintani, Kazuki Oishi, Rui Zhou, Masayuki Hiromoto and Takashi Sato. [Unique Device Identification Framework for Power MOSFETs Using Inherent Device Variation](#)

Shumpei Morita, Song Bian, Michihiro Shintani, Masayuki Hiromoto and Takashi Sato. [Representative Path Approach for Time-Efficient NBTI Mitigation Logic Replacement](#)

Alan Carlos Junior Rossetto, Vinicius Valduga de Almeida Camargo, Dragica Vasileska and Gilson Inacio Wirth. [Novel State-of-the-Art Monte Carlo Device Simulator for Modeling RDF, RTN and NBTI Using Real-Space Treatment of the Coulomb Interactions and Self-Heating Effects](#)
